54AC11534 ... JT PACKAGE 74AC11534 ... DW OR NT PACKAGE

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- Eight D-Type Flip-Flops in a Single Package
- 3-State Bus Driving Inverting Outputs
- Full Parallel Access for Loading
- Inputs Are TTL-Voltage Compatible
- Flow-Through Architecture to Optimize PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations to Minimize High-Speed Switching Noise
- *EPIC*<sup>™</sup> (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

### description

These eight flip-flops feature 3-state outputs designed for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

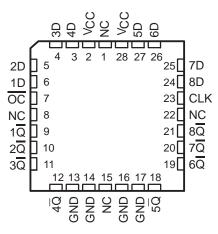
The eight flip-flops of the 'AC11534 are edgetriggered, D-type flip-flops. On the positive transition of the clock, the  $\overline{Q}$  outputs are set to the complement of the logic levels at the D inputs. The 'AC11534 is functionally equivalent to the 'AC11374 except for having inverted outputs.

An output-control input  $(\overline{OC})$  is used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance third state and increased drive provide the capability to drive the bus lines in a bus-organized system without need for interface or pull-up components. The output control  $(\overline{OC})$  does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The 54AC11534 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The 74AC11534 is characterized for operation from  $-40^{\circ}$ C to 85°C.

	(TOP	VIEW)	)
1Q[	1	J <sub>24</sub>	
2Q	2	23	1D
3 <u>Q</u> [	3	22	2D
4 <u>Q</u> [	4	21	] 3D
GND [	5	20	] 4D
GND [	6	19	Vcc
GND [	7	18	Vcc
GND [	8	17	] 5D
5Q [	9	16	] 6D
6Q [	10	15	] 7D
7Q [	11	14	] 8D
8 <u>Q</u> [	12	13	] CLK

#### 54AC11534 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

#### FUNCTION TABLE (each filp-flop)

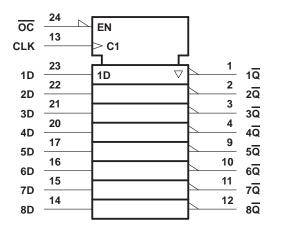
	INPUTS		OUTPUT
	CLK	D	Q
L	$\uparrow$	Н	L
L	$\uparrow$	L	Н
L	L	Х	$\overline{Q}_0$
н	Х	Х	Z

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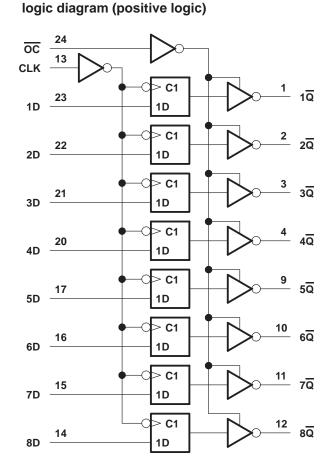
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



Pin numbers shown are for the DW, JT, and NT packages.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	-0.5  V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 1)	-0.5  V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub> )	$\pm 20 \text{ mA}$
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	± 50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	± 50 mA
Continuous current through V <sub>CC</sub> or GND	± 200 mA
Storage temperature range	

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



## 54AC11534, 74AC11534 OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS SCAS037A – JULY 1987 – REVISED APRIL 1993

## recommended operating conditions

			54	4AC1153	4	74	AC1153	4	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	3	5	5.5	V
		$V_{CC} = 3 V$	2.1			2.1			
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V
		V <sub>CC</sub> = 5.5 V	3.85			3.85			
		$V_{CC} = 3 V$			0.9			0.9	
VIL	Low-level input voltage	$V_{CC} = 4.5 V$			1.35			1.35	V
		V <sub>CC</sub> = 5.5 V			1.65			1.65	
VI	Input voltage		0		Vcc	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		V <sub>CC</sub> = 3 V			- 4			- 4	
ЮН	High-level output current	$V_{CC} = 4.5 V$			- 24			- 24	mA
		V <sub>CC</sub> = 5.5 V			-24			-24	
		$V_{CC} = 3 V$			12			12	
IOL	Low-level output current	$V_{CC} = 4.5 V$			24			24	mA
		V <sub>CC</sub> = 5.5 V			24			24	
Δt/Δv	Input trappition rise or fall rate	OC	0		5	0		5	ns/V
Δι/Δν	Input transition rise or fall rate	D	0		10	0		10	115/ V
TA	Operating free-air temperature		-55		125	- 40		85	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vee	Т	<b>₄ = 25°C</b>		54AC	11534	74AC11534		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		2.9		
	I <sub>OH</sub> = - 50 μA	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
Veri	I <sub>OH</sub> = - 4 mA	3 V	2.58			2.4		2.48		V
VOH	I <sub>OH</sub> = – 24 mA	4.5 V	3.94			3.7		3.8		v
	-	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
					0.1		0.1		0.1	
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V
		5.5 V			0.1		0.1		0.1	
VOL	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	
VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44	v
		5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
I <sub>OZ</sub>	$V_{O} = V_{CC}$ or GND	5.5 V			± 0.5		± 10		± 5	μΑ
l	$V_{I} = V_{CC} \text{ or } GND$	5.5 V			± 0.1		± 1		± 1	μA
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			8		160		80	μA
Ci	$V_I = V_{CC}$ or GND	5 V		4						pF
Co	$V_{O} = V_{CC} \text{ or } GND$	5 V		10						pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



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## timing requirements, V<sub>CC</sub> = 3.3 V $\pm$ 0.3 V (see Figure 1)

		T <sub>A</sub> = 25°C		54AC11534		4 74AC11534		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency	0	50	0	50	0	50	MHz
tw	Pulse duration, CLK low or CLK high	10		10		10		ns
t <sub>su</sub>	Setup time, data before CLK $\uparrow$	3.5		3.5		3.5		ns
th	Hold time, data after CLK $\uparrow$	5.5		5.5		5.5		ns

## timing requirements, V<sub>CC</sub> = 5 V $\pm$ 0.5 V (see Figure 1)

		T <sub>A</sub> = 25°C		54AC11534		74AC11534		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency	0	75	0	75	0	75	MHz
t <sub>W</sub>	Pulse duration, CLK low or CLK high	6.5		6.5		6.5		ns
t <sub>su</sub>	Setup time, data before CLK $\uparrow$	3.5		3.5		3.5		ns
t <sub>h</sub>	Hold time, data after CLK $\uparrow$	4.5		4.5		4.5		ns

## switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	λ = 25°C	;	54AC1	1534	74AC1	1534	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
f <sub>max</sub>			50	75		50		50		MHz	
<sup>t</sup> PLH	CLK	CLK	-	1.5	11	15.3	1.5	19.1	1.5	17.6	
<sup>t</sup> PHL		Q	1.5	11	15.7	1.5	19	1.5	17.7	ns	
<sup>t</sup> PZH	<u>oc</u>	-	1.5	9	12.8	1.5	15.8	1.5	14.6	ns	
<sup>t</sup> PZL	00	Q	1.5	9	12.6	1.5	15.6	1.5	14.3	115	
<sup>t</sup> PHZ	OC		1.5	10	12.6	1.5	13.8	1.5	13.3		
tPLZ	00	Q	1.5	8	13	1.5	14.2	1.5	13.8	ns	

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

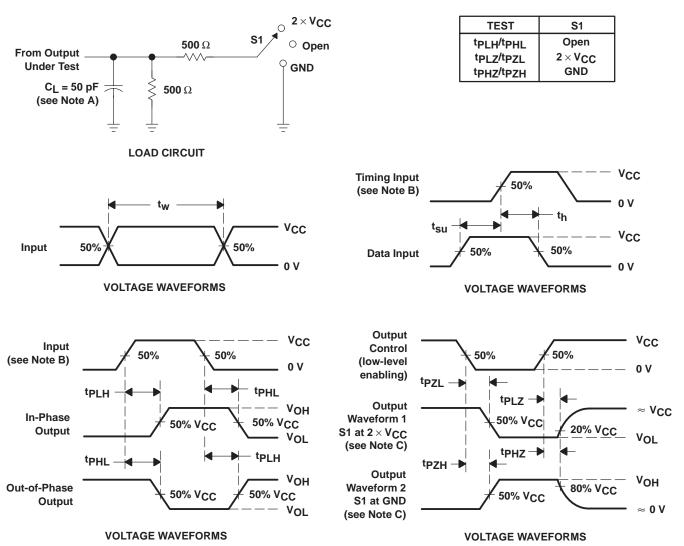
PARAMETER	FROM	то	Тį	ς = 25°C	;	54AC1	1534	74AC1	1534	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f <sub>max</sub>			75	100		75		75		MHz
<sup>t</sup> PLH	CLK	ā	1.5	7	10.3	1.5	12.7	1.5	11.7	
<sup>t</sup> PHL			1.5	7	10.7	1.5	13.2	1.5	12.1	ns
<sup>t</sup> PZH	OC	Q	1.5	6	9.2	1.5	11.2	1.5	10.4	20
<sup>t</sup> PZL		Q	1.5	6	9.2	1.5	11.3	1.5	10.4	ns
<sup>t</sup> PHZ	<del>oc</del>	Q	1.5	9	11.1	1.5	11.9	1.5	11.6	ns
<sup>t</sup> PLZ		Q	1.5	6	8.8	1.5	9.6	1.5	9.2	115

## operating characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT	
C Dewer dissinction conseitance per flip flep		Outputs enabled	Ci = 50 pF. f = 1 MHz	75	nE
Cpd	Power dissipation capacitance per flip-flop	Outputs disabled	$C_L = 50 \text{ pF}, \text{ f} = 1 \text{ MHz}$	65	PF



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### PARAMETER MEASUREMENT INFORMATION

NOTES: A. C<sub>1</sub> includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub> = 3 ns, t<sub>f</sub> = 3 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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